


<b>Search Notes</b> 	<b>Application/Control No.</b> 10586359	<b>Applicant(s)/Patent Under Reexamination</b> ABE ET AL.
	<b>Examiner</b> SHEELA C CHAWAN	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	181, 190, 192, 199, 203, 254, 162, 164, 173, 263, 264	2/28/10	SCC
503	201, 226, 202, 211,	"	"
101	467, 458, 453, 465, 470	"	"
355	22, 46,	"	"
219	121.7	"	"
347	8, 102, 43, 171, 19	"	"
428	329, 914, 172, 916, 207, 208, 913, 317.9, 320.2, 164, 165,	"	"
382	181, 164, 263, 264	8/14/10	SCC
503	202	8/14/10	SCC
347	43	8/14/10	SCC
428	207	8/14/10	SCC
SEARCH UP-DATE		8/14/10	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	2/28/10	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST AND OTHER DATA BASE SEE THE SEARCH HISTORY.	8/14/10	SCC
382/181, 190, 192, 199, 203, 254, 162, 164, 173, 263, 264. CCLS. TEXT SEARCH ONLY.	8/14/10	SCC
503/201, 226, 202, 211, 210.CCLS.	8/14/10	SCC
347/8, 102, 43, 171, 19. CCLS.	8/14/10	SCC
428/ 329, 914, 172, 916, 207, 208, 913, 317.9, 320.2, 164, 165.CCLS.	8/14/10	SCC
INTERFERENCE SEARCH	8/14/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	8/14/10	SCC
SEARCH UP-DATE.	8/14/10	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	181, 164, 263, 264	8/14/10	SCC

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# INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
503	202	8/14/10	SCC
347	43	8/14/10	SCC
428	207	8/14/10	SCC

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